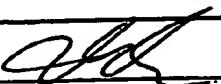


Form PTO 1449 (Modified)  U.S. DEPARTMENT OF COMMERCE PATENT & TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT		ATTY DOCKET NO. 198092US-2S DIV		SERIAL NO. 09/684,904	
		APPLICANT HIRONOBU KON, ET AL.			
		RCE FILED DECEMBER 19, 2002		GROUP 2814	
		U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUB CLASS
	AA				
	AB				
	AC				
	AD				
	AE				
	AF				
	AG				
	AH				
	AI				
	AJ				
	AK				
	AL				
	AM				
	AN				
FOREIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES      NO
<i>DF</i>	AP	JP- 08-162631	06/21/96	Japan	<input type="checkbox"/> <input checked="" type="checkbox"/>
<i>DR</i>	AQ	JP 10-229671	08/25/98	Japan	<input type="checkbox"/> <input checked="" type="checkbox"/>
	AR				
	AS				
	AT				
	AU				
	AV				
	AW				
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)					
	AX				
	AY				
	AZ				
	AZ				
Examiner	<i>Da Shi</i>			Date Considered	<i>5/26/05</i>
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

10/10/00

SHEET 1 OF 2

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 198092US-2S DIV		SERIAL NO. New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Hironobu KON et al			
		FILING DATE		Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TT	AA	5,729,032	03/1998	TOMOMATSU ET AL			
TT	AB	5,610,439	03/11/97	HIYOSHI ET AL			
TT	AC	5,530,277	06/1996	OTSUKI ET AL			
TT	AD	5,448,083	09/05/95	KITAGAWA ET AL			
TT	AE	5,329,142	07/12/94	KITAGAWA ET AL			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
DF	AO	44 29733 A1	3/1995	GERMANY (with abstract)	YES	NO	X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
TT	AW	Hideo Matsuda, "Pressure Contact Assembly Technology of High Power Devices," Power Semiconductor Devices and ICs. 1997. ISPSD '97 1997 IEEE International Symposium on, May 1997, pp. 17-24.					
TT	AX	M. Kudoh, et al., "Current Sensing IGBT for Future Intelligent Power Module," Power Semiconductor Devices and ICs. 1998. ISPSD '98 Proceedings.,8th International Symposium on, May 1998, pp. 303-306.					
TT	AY	Mitsuhiko Kitagawa, et al., "A 4500V Injection Enhanced Insulated Gate Bipolar Transistor (IEGT) Operating in a Mode Similar to a Thyristor,"IEDM, December 1993, pp. 679-682.					
TT	AZ	Noriyuki Iwamuro, "A New Vertical IGBT Structure with a Monolithic Over-Current, Over-Voltage, and Over-Temperature Sensing and Protecting Circuit," IEEE Electron Device Lett., Vol. 16, No. 9, September 1995, pp. 399-401.					
Examiner 				Date Considered 10/07/00			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1448 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 198092US-2S DIV	SERIAL NO. New Divisional Application
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Hironobu KON et al			
		FILING DATE Herewith	GROUP 2814		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)					
TT	AAA	Yasukazu Seki, et al., "A New IGBT with a Monolithic Over-Current Protection Circuit," Proc. of the 6 <sup>th</sup> Internat. Symposium on Power Semiconductor Davos, Switzerland, May 31-June 2, 1994, pp. 31-35.			
	AAB				
	AAC				
	AAD				
	AAE				
	AAF				
	AAG				
	AAH				
	AAI				
	AAJ				
	AAK				
	AAL				
	AAM				
	AAN				
	AAO				
	AAP				
	AAQ				
Examiner <i>herb</i>			Date Considered 10/02/01		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					